


<b>Search Notes</b>  	<b>Application/Control No.</b>  10769930	<b>Applicant(s)/Patent Under Reexamination</b>  CHUNG ET AL.
	<b>Examiner</b>  ALI BAYAT	<b>Art Unit</b>  2624

### SEARCHED

Class	Subclass	Date	Examiner
382	100,115,119,121-122,187,219,305	2/26/08	A.B
348	161	2/26/08	A.B
345	179	2/26/08	A.B
73	865.4	2/26/08	S.B
178	18.01	2*26/08	A.B
	updated above	6/19/08	A.B

### SEARCH NOTES

Search Notes	Date	Examiner
EAST( US-PGPUB; USPAT; EPO;JPO;DERWENT; USOCR; FPRS), Inventor name searched,see text search history print out.	2/26/08	A.B
updated above pluse IEEE EXPLORE DATABASE searched.	6/19/08	A.B

### INTERFERENCE SEARCH

Class	Subclass	Date	Examiner
US-PGPUB	see Interference search history print out.	2/26/08	A.B
	updated above	6/19/08	A.B